

# SCHOTTKY DIODES KDN-20060.



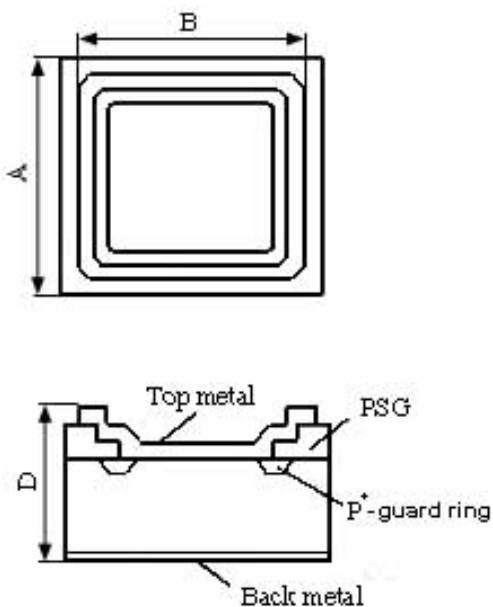
Rev.1. Feb. 2010



**VSP-MIKRON**

**20A/60V. Die Size-106\*138mil.**

Electrical Characteristics	Symbol	Unit	Spec. limit	Die Sort
Breakdown Voltage @ $I_R=10\text{mA}$	$V_{BR}$	V	60	65
Average Rectified Forward Current	$I_{F(AV)}$	A	20,0	-
DC Forward Voltage @ $25^\circ\text{C}$ , $I_F=20,0\text{A}$	$V_F$	V	0,65	0,63
Maximum Reverse Current @ $25^\circ\text{C}$ , $V_R=65\text{V}$ $25^\circ\text{C}$ , $V_R=60\text{V}$ $125^\circ\text{C}$ , $V_R=60\text{V}$	$I_R$	mA	- 0,350 0,300 200,0	0,350 0,300 190,0
Peak Forward Surge Current 8,3ms single half sine-wave superimposed on rated load (JEDEC METHOD)	$I_{FSM}$	A	250	-
Peak Repetitive Reverse Surge Current @ $2,0\mu\text{s}$ , $f=1\text{kHz.}$ , $T_J<150^\circ\text{C.}$	$I_{RRM}$	A	4,5	
Electrostatic Discharge Voltage. JEDEC Method. ESD HBM. Contact.	ESD	kV	$\pm 8$ (contact)	
Voltage Rate of Change	$dV/dt$	V/ $\mu\text{S}$	10.000	
Operating Junction Temperature	$T_J$	°C	150	



DIM	ITEM	µm
$A_x$	Wafer Form Die Size	2700
$A_y$		3500
$B_x$	Top Metal Size	2560
$B_y$		3360
D	Thickness	350max.
Scribe line Width		80

*Top metal:* a) **Al** – for Wire Bonding;  
b) **Al-Ni-Ag** – for Soldering.

*Backside metal:* **Ti-Ni-Ag**.